## Notice of References Cited Application/Control No. | Applicant(s)/Patent Under | Reexamination | CHANG ET AL. | Examiner | Art Unit | Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6,814,832	11-2004	Utsunomiya, Sumio	156/230
	В	US-6,861,802	03-2005	Hishida, Mitsuoki	313/512
	С	US-2004/0097161	05-2004	Gourlay, James	445/024
	D	US-2004/0214380	10-2004	Leib et al.	438/151
	Е	US-2002/0139981	10-2002	Young, Nigel D.	257/72
	F	US-			
	G	US-			
	Н	US-			
	1	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R					
	S					
	Т					

## NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	v	
	w	
	х	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.